

isc N-Channel MOSFET Transistor

IRFP4768, IIRFP4768

• FEATURES

- Static drain-source on-resistance:
 $R_{DS(on)} \leq 17.5\text{m}\Omega$
- Enhancement mode:
- 100% avalanche tested
- Minimum Lot-to-Lot variations for robust device performance and reliable operation

• DESCRIPTION

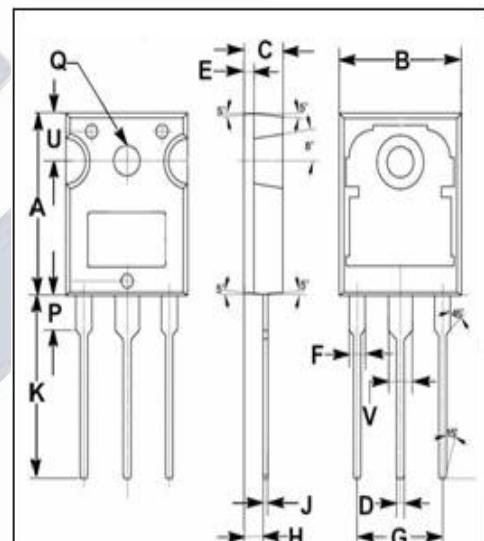
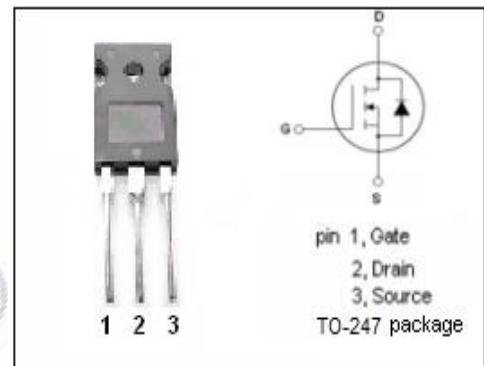
- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched And High Frequency Circuits

• ABSOLUTE MAXIMUM RATINGS($T_a=25^\circ\text{C}$)

| SYMBOL | PARAMETER | VALUE | UNIT |
|-----------|--|----------|------------------|
| V_{DSS} | Drain-Source Voltage | 250 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| I_D | Drain Current-Continuous | 93 | A |
| I_{DM} | Drain Current-Single Pulsed | 370 | A |
| P_D | Total Dissipation @ $T_c=25^\circ\text{C}$ | 520 | W |
| T_j | Max. Operating Junction Temperature | 175 | $^\circ\text{C}$ |
| T_{stg} | Storage Temperature | -55~175 | $^\circ\text{C}$ |

• THERMAL CHARACTERISTICS

| SYMBOL | PARAMETER | MAX | UNIT |
|---------------|---------------------------------------|------|---------------------------|
| $R_{th(j-c)}$ | Channel-to-case thermal resistance | 0.29 | $^\circ\text{C}/\text{W}$ |
| $R_{th(j-a)}$ | Channel-to-ambient thermal resistance | 40 | $^\circ\text{C}/\text{W}$ |



| DIM | mm | |
|-----|-------|-------|
| | MIN | MAX |
| A | 19.80 | 20.20 |
| B | 15.40 | 15.80 |
| C | 4.90 | 5.10 |
| D | 0.90 | 1.10 |
| E | 1.40 | 1.60 |
| F | 1.90 | 2.10 |
| G | 10.80 | 11.00 |
| H | 2.40 | 2.60 |
| J | 0.50 | 0.70 |
| K | 19.50 | 20.50 |
| P | 3.90 | 4.10 |
| Q | 3.30 | 3.50 |
| U | 5.20 | 5.40 |
| V | 2.90 | 3.10 |

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ELECTRICAL CHARACTERISTICS

 $T_c=25^\circ\text{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------------------|--------------------------------|---|-----|-----|-----------|------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $\text{V}_{\text{GS}}=0\text{V}; \text{I}_D=250 \mu\text{A}$ | 250 | | | V |
| $\text{V}_{\text{GS(th)}}$ | Gate Threshold Voltage | $\text{V}_{\text{DS}}=\text{V}_{\text{GS}}; \text{I}_D=250 \mu\text{A}$ | 3.0 | | 5.0 | V |
| $\text{R}_{\text{DS(on)}}$ | Drain-Source On-Resistance | $\text{V}_{\text{GS}}=10\text{V}; \text{I}_D=56\text{A}$ | | | 17.5 | $\text{m}\Omega$ |
| I_{GSS} | Gate-Source Leakage Current | $\text{V}_{\text{GS}}= \pm 20\text{V}$ | | | ± 0.1 | μA |
| I_{DSS} | Drain-Source Leakage Current | $\text{V}_{\text{DS}}=250\text{V}; \text{V}_{\text{GS}}= 0\text{V}$ | | | 20 | μA |
| V_{SD} | Diode forward voltage | $\text{I}_S=56\text{A}, \text{V}_{\text{GS}} = 0\text{V}$ | | | 1.3 | V |